Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/790,394	TANAKA ET AL.	
Examiner	Art Unit	

Alvin C. Chin-Shue

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		Subclass Date		

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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